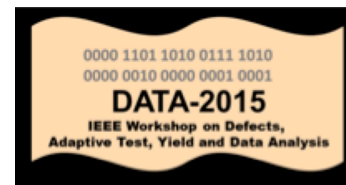


DATA-2015: IEEE INTERNATIONAL WORKSHOP on DEFECTS, ADAPTIVE TEST, YIELD AND DATA ANALYSIS

Will be held in conjunction with ITC 2015, on Oct 8/9 2015, at the Disneyland Hotel, Anaheim, CA



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CALL FOR PAPERS AND PARTICIPATION THEME: "YIELD LEARNING"

Every year, we revisit the scope of the DATA workshop to capture emerging issues, but the common theme has always been DATA, specifically, semiconductor test and yield data. We need to not only measure and collect data, but also to process the data appropriately for yield analysis. The data can come from a variety of sources, including test sort & fail bins, in-line defect inspection, test measurements, memory bitmapping, scan diagnosis, and physical failure analysis. There is a need to aggregate, overlay, and cross-correlate the data from these various sources in a way that allows efficient yield learning and enables a speedy production ramp.

The Organizing Committee for the DATA-2015 Workshop is soliciting papers in the area of semiconductor yield analysis, learning, and improvement. Of particular interest are advanced techniques and new tools for faster data-driven yield learning, data acquisition, the statistical analysis of yield loss in semiconductor manufacturing, and implementation of adaptive test. Preference will be given to real-world case studies.

Ideas or proposals for Embedded Tutorials, Debates, Panel Discussions and **Poster style "Spot-Light"** presentations describing industrial experiences or research are also invited.

Suggested Topics

Yield Learning and Analysis
Analog Fault modeling and coverage
Analog effects in Digital Logic
Embedded Instrumentation (iJTAG)
Advanced Product Engineering Techniques
Product and Project Case studies
Advanced dppm reduction & reliability improvement techniques

Data Acquisition & Transport
Dynamic test elimination based on data
Adaptive Test for Product Engineers
Data Analysis methods, including multivariate data
Fault Localization and Diagnosis
Data storage and security
I/O Test, Tuning, and Adjustment

To present at the workshop, send to jdworak@lyle.smu.edu a PDF version of an extended abstract or a full paper (Max 10 pages, double column, 11pt font size, [IEEE proceeding format](#)) by **August 15, 2015**. Each submission should include full name and address of each author, affiliation, telephone number, FAX and Email address. Camera-ready papers for inclusion in the digest of papers will be due on **September 22, 2015**.

AUTHOR'S SCHEDULE

Submission Date: August 15, 2015
Notification of Acceptance: August 29, 2015
Camera Ready Paper (.pdf): September 22, 2015
Final Presentation Slides (.ppt): October 1, 2015

Web-site at: <http://DATA.tttc-events.org/>

Technical Program Submissions:

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DATA-2015 is sponsored by:

